Irish Standard
I.S. EN 62047-7:2011

Semiconductor devices - Micro-electromechanical devices -- Part 7: MEMS BAW filter and duplexer for radio frequency control and selection (IEC 62047-7:2011 (EQV))

I.S. EN 62047-7:2011

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English version

Semiconductor devices - Micro-electromechanical devices - Part 7: MEMS BAW filter and duplexer for radio frequency control and selection
(IEC 62047-7:2011)

Dispositifs à semiconducteurs -
Dispositifs microélectromécaniques -
Partie 7: Filtre et duplexeur BAW MEMS pour la commande et le choix des fréquences radioélectriques
(CEI 62047-7:2011)

Halbleiterbauelemente -
Bauelemente der Mikrosystemtechnik -
Teil 7: BAW-MEMS-Filter und -Duplexer zur Hochfrequenz-Regelung und -Auswahl
(IEC 62047-7:2011)

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Europäisches Komitee für Elektrotechnische Normung

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Foreword

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The following dates were fixed:

– latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2012-04-21
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Endorsement notice

The text of the International Standard IEC 62047-7:2011 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60368-1:2000 + A1:2004	NOTE Harmonized as EN 60368-1:2000 + A1:2004 (not modified).
IEC 60368-2-2	NOTE Harmonized as EN 60368-2-2.
IEC 60862-1:2003	NOTE Harmonized as EN 60862-1:2003 (not modified).
IEC 60862-2	NOTE Harmonized as EN 60862-2.

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SEMICONDUCTOR DEVICES –
MICRO-ELECTROMECHANICAL DEVICES –

Part 7: MEMS BAW filter and duplexer for radio frequency control and selection

FOREWORD

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47F/79/FDIS	47F/87/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

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